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APPLICATION NO. FILING DATE FIRST NAMED INVENTOR ATTORNEY DOCKET NO. W CA1028 BAER 12/23/98 09/220,293 **EXAMINER** TM01/0914 VEILLARD, J

SUGHRUE MION ZINN MACPEAK AND SEAS 1010 EL CAMINO REAL SUITE 360 MENLO PARK CA 94025

ART UNIT PAPER NUMBER 2171 DATE MAILED:

09/14/01

Please find below and/or attached an Office communication concerning this application or proceeding.

Commissioner of Patents and Trademarks

Application No. 09/220,293

Applicant(s)

William J. Baer et al.

Examiner

Group Art Unit 2171 Jacques Veillard



Interview Summary

All participants (applicant, applicant's representative, PTO	personnel):		
(1) <u>Jacques Veillard</u>	(3) Frank L. Bernstein		
(2) <u>Dr. Wayne Amsbery</u>	(4) Lin Deng		
Date of Interview Sep 11, 2001	-		
Type: a) ☑ Telephonic b) ☐ Video Conference c) ☐ Personal (copy is given to 1) ☐ applicant Exhibit shown or demonstration conducted: d) ☐ Yes			
Claim(s) discussed: 1			
Identification of prior art discussed: Mullins (U. S. Patent 5,857,197) Agreement with respect to the claims f) was reached. g) was not reached. h N/A. Substance of Interview including description of the general nature of what was agreed to if an agreement was reached, or any other comments:			
		Applicant's position is that Mullins does not teach write to the data store.	
	· · ·		
			
	dments which the examiner agreed would render the claims copy of the amendments that would render the claims allowable is		
i) It is not necessary for applicant to provide a separation	rate record of the substance of the interview (if box is checked).		
INCLUDE THE SUBSTANCE OF THE INTERVIEW. (See MP already been filed, APPLICANT IS GIVEN ONE MONTH FRO	AL WRITTEN REPLY TO THE LAST OFFICE ACTION MUST EP section 713.04). If a reply to the last Office action has DM THIS INTERVIEW DATE TO FILE A STATEMENT OF THE d of Interview requirements on reverse side or on attached		
	Month		

THOMAS BLACK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2100